

FCC ID: 2ABNJ-BV150

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)]·√f(GHz) ≤ 3.0 for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where:

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

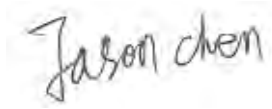
Modulation	Channel Freq. (GHz)	Conduct ed power (dBm)	Conducte d power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	1g SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	0.95	1.245	1±1	2	1.585	<5	0.49127	3.00	YES
	2.441	1.23	1.327	1±1	2	1.585	<5	0.49524	3.00	YES
	2.480	1.16	1.306	1±1	2	1.585	<5	0.49918	3.00	YES
π/4-DQPSK	2.402	-0.93	0.807	0±1	1	1.259	<5	0.39023	3.00	YES
	2.441	-0.28	0.938	0±1	1	1.259	<5	0.39338	3.00	YES
	2.480	-0.39	0.914	0±1	1	1.259	<5	0.39651	3.00	YES
8DPSK	2.402	-0.77	0.838	0±1	1	1.259	<5	0.39023	3.00	YES
	2.441	-0.08	0.982	0±1	1	1.259	<5	0.39338	3.00	YES
	2.480	-0.41	0.910	0±1	1	1.259	<5	0.39651	3.00	YES

BLE:

[illegible]

Conclusion:

For the max result : $0.49918 \leq 3.0$ for 1-g SAR, No SAR is required.

A handwritten signature in black ink that reads "Jason chen". The signature is written in a cursive, slightly slanted style.**Signature:****Date:** 2017-01-18**NAME AND TITLE** (Please print or type): Jason Chen /Manager**COMPANY** (Please print or type): Shenzhen NTEK Testing Technology Co., Ltd./ 1/F, Building E,
Fenda Science Park, Sanwei Community, Xixiang Street Bao'an District, Shenzhen P.R. China.